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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/083,684	02/27/2002	Tomonari Yamamoto	020254	1544
38834	7590 11/03/2004		EXAMINER	
WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP			ERDEM, FAZLI	
1250 CONNECTICUT AVENUE, NW SUITE 700		ART UNIT	PAPER NUMBER	
	N, DC 20036	2826	·	
			DATE MAILED: 11/03/2004	

Please find below and/or attached an Office communication concerning this application or proceeding.

		M /				
	Application No.	Applicant(s)				
	10/083,684	YAMAMOTO, TOMONARI				
Office Action Summary	Examiner	Art Unit				
	Fazli Erdem	2826				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply						
A SHORTENED STATUTORY PERIOD FOR REPL' THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a repl - If NO period for reply is specified above, the maximum statutory period of the period for reply within the set or extended period for reply will, by statute any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be ting within the statutory minimum of thirty (30) day will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	mely filed ys will be considered timely. the mailing date of this communication. ED (35 U.S.C.§ 133).				
Status						
1) Responsive to communication(s) filed on <u>06 A</u>	<u>ugust 2004</u> .					
· <u> </u>	action is non-final.					
	3) Since this application is in condition for allowance except for formal matters, prosecution as to the ments is					
closed in accordance with the practice under E	<i>x par</i> te Quayle, 1935 C.D. 11, 4:	53 O.G. 213.				
Disposition of Claims		•				
4)	wn from consideration.	n.				
7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/o	r election requirement.					
Application Papers						
9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) acc Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Ex	epted or b) objected to by the drawing(s) be held in abeyance. Se ion is required if the drawing(s) is ob	e 37 CFR 1.85(a). ojected to. See 37 CFR 1.121(d).				
Priority under 35 U.S.C. § 119						
a) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list	s have been received. s have been received in Applicat rity documents have been receive u (PCT Rule 17.2(a)).	ion No ed in this National Stage				
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal F 6) Other:					

U.S. Patent and Trademark Office PTOL-326 (Rev. 1-04)

DETAILED ACTION

Allowable Subject Matter

1. Claims 1-4, 6-10, 12-14, 16-19, 21-23 25 and 26 allowed.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 27 and 28 rejected under 35 U.S.C. 103(a) as being unpatentable over Talwar et al. (6,380,04) in view of Guegan (5,705,410).

Regarding Claims 27 and 28, Talwar et al. disclose a high speed semiconductor transsitor and selective absorption process forming same where in Fig. 1E, shallow source extension 60, shallow drain extension 62, deep source extension 80, deep drain extension 84 are formed under gate structure 36 and in single crystal 10. Source/drain extensions include dopants/impurities for amorphization. Talwar et al. fail to disclose the seeping of source/drain extension under the gate structure and the required capacitance value. However, Guegan disclose method of producing a semiconductor with a highly doped zone situated between lightly doped zones for the manufacture of transistors where in Fig. 2, source/drain extensions are under the gate and the required capacitance value is disclosed in column 7.

It would have been obvious to one of having ordinary skill in the art at the time the invention was made to include the required seeping of source/drain under the gate and

the required capacitance value in Talwar et al. as taught by Guegan in order to have a semiconductor structure with increased performance.

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4. Claims 29 and 30 rejected under 35 U.S.C. 103(a) as being unpatentable over Talwar et al. (6,380,04) in view of Guegan (5,705,410) further in view of Chou et al. (5,308,780)

Regarding Claims 29 and 30, Talwar et al. disclose a high speed semiconductor transsitor and selective absorption process forming same where in Fig. 1E, shallow source extension 60, shallow drain extension 62, deep source extension 80, deep drain extension 84 are formed under gate structure 36 and in single crystal 10. Source/drain extensions include dopants/impurities for amorphization. Talwar et al. fail to disclose the seeping of source/drain extension under the gate structure, the required capacitance value, and the required larger tilt angle on one of the source/drain sides. However, Guegan disclose method of producing a semiconductor with a highly doped zone situated between lightly doped zones for the manufacture of transistors where in Fig. 2, source/drain extensions are under the gate and the required capacitance value is disclosed in column 7. Furthermore, Chou et al. disclose surface counter-doped N-LDD for high hot carrier reliability where in Fig. 3, larger tilt angle on one of the source/drain sides is disclosed.

It would have been obvious to one of having ordinary skill in the art at the time the invention was made to include the required seeping of source/drain under the gate, the required capacitance value, and the required larger tilt angle on one of the source/drain sides in Talwar et al. as taught by Guegan and Thou et al. respectively in order to have a semiconductor structure with increased performance.

Conclusion

Application/Control Number: 10/083,684

Art Unit: 2826

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Fazli Erdem whose telephone number is (571) 272-1914. The examiner can normally be reached on M - F 8:00 - 5:00.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan Flynn can be reached on (571) 272-1915. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

FE October 25, 2004